

Notice of References Cited	Application/Control No. 10/663,714	Applicant(s)/Patent Under Reexamination INOUE ET AL.	
	Examiner A. Sefer	Art Unit 2826	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0190263	12-2002	Hata et al.	257/103
	B	US-2002/0074556	06-2002	Kwak et al.	257/79
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2000-299497	10-2000	Japan	Nagahama et al	
	O	JP 2001-77412	03-2001	Japan	Nomura et al	
	P	JP 2003-243772	08-2003	Japan	Takeya et al.	
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.